Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/773,153	EGUCHI ET AL.	
Examiner	Art Unit	
Anh T. Mai	2832	

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INTERFERENCE SEARCHED			
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336/200,223,232 [text only] search history printout	9/26/2025	AM
323/361,305,355[text only] search history printout	9/26/2005	АМ
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